

ZXMN3F30FH 30V SOT23 N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	$R_{DS(on)}\left(\Omega\right)$	I _D (A)
30	0.047 @ V _{GS} = 10V	4.6
	0.065 @ V _{GS} = 4.5V	4.0

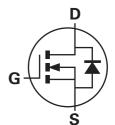


Description

This new generation Trench MOSFET from Zetex features low onresistance achievable with 4.5V gate drive.

Features

- · Low on-resistance
- 4.5V gate drive capability
- SOT23

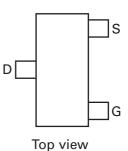


Applications

- · DC-DC Converters
- · Power management functions
- Motor Control

Ordering information

DEVICE	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN3F30FHTA	7	8	3000



Device marking

KNA

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain source voltage	V _{DSS}	30	V
Gate source voltage	V _{GS}	±20	V
Continous Drain Current @ V _{GS} =4.5; T _A =25°C ^(b)	I _D	4.6	Α
@ V _{GS} =4.5; T _A =70°C ^(b)		3.7	Α
@ V _{GS} =4.5; T _A =25°C ^(a)		3.8	Α
Pulsed drain current ^(c)	I _{DM}	21	А
Continuous source current (body diode)(b)	I _S	2.2	А
Pulsed source current (body diode)(c)	I _{SM}	21	Α
Power dissipation at T _A =25°C ^(a)	P _D	0.95	W
Linear derating factor		7.6	mW/°C
Power dissipation at T _A =25°C ^(b)	P _D	1.4	W
Linear derating factor		11.2	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^(a)	$R_{\Theta JA}$	131	°C/W
Junction to ambient ^(b)	$R_{\Theta JA}$	89	°C/W
Junction to lead ^(d)	$R_{\Theta JL}$	68	°C/W

NOTES

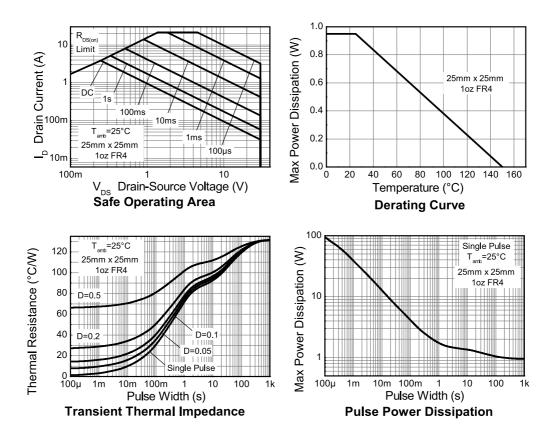
⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

⁽b) For a device surface mounted on FR4 PCB measured at $t \leq 5 \mbox{ sec.}$

⁽c) Repetitive rating - $25mm \times 25mm \text{ FR4 PCB}$, D=0.02, pulse width $300\mu\text{s}$ - pulse width limited by maximum junction temperature.

⁽d) Thermal resistance from junction to solder-point (at the end of the drain lead).

Thermal characteristics



Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions	
Static							
Drain-Source breakdown Voltage	V _{(BR)DSS}	30			V	I _D = 250μA, V _{GS} =0V	
Zero gate voltage drain current	I _{DSS}			0.5	μΑ	V _{DS} = 30V, V _{GS} =0V	
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V	
Gate-Source threshold voltage	V _{GS(th)}	1.0		3.0	V	$I_D=250\mu A,\ V_{DS}=V_{GS}$	
Static Drain-Source on-state resistance (*)	R _{DS(on)}			0.047 0.065	Ω Ω	V _{GS} = 10V, I _D = 3.2A V _{GS} = 4.5V, I _D = 2.8A	
Forward transconductance ^{(*)(†)}	9 _{fs}		5.2		S	V _{DS} = 15V, I _D = 2.5A	
Dynamic ^(†)							
Input capacitance	C _{iss}		318		рF	V _{DS} = 15V, V _{GS} =0V f=1MHz	
Output capacitance	C _{oss}		75		pF		
Reverse transfer capacitance	C _{rss}		45		pF		
Switching ^{(†) (‡)}							
Turn-on-delay time	t _{d(on)}		1.6		ns		
Rise time	t _r		2.6		ns	V _{DD} = 15V, V _{GS} = 10V I _D = 1A	
Turn-off delay time	t _{d(off)}		17		ns	$R_{\rm G} \approx 6.0\Omega$	
Fall time	t _f		9.3		ns		
Total gatecharge	Q_g		7.7		nC	V _{DS} = 15V, V _{GS} = 10V	
Gate-Source charge	Q _{gs}		1		nC	I _D = 2.5A	
Gate-Drain charge	Q _{gd}		1.8		nC		
Source-drain diode						•	
Diode forward voltage(*)	V_{SD}		0.73	1.2	V	I _S = 1.25A, V _{GS} =0V	
Reverse recovery time ^(†)	t _{rr}		12		ns	T _j =25°C, I _F =1.6A	
Reverse recovery charge ^(†)	Q _{rr}	_	4.8		nC	di/dt=100A/μs	

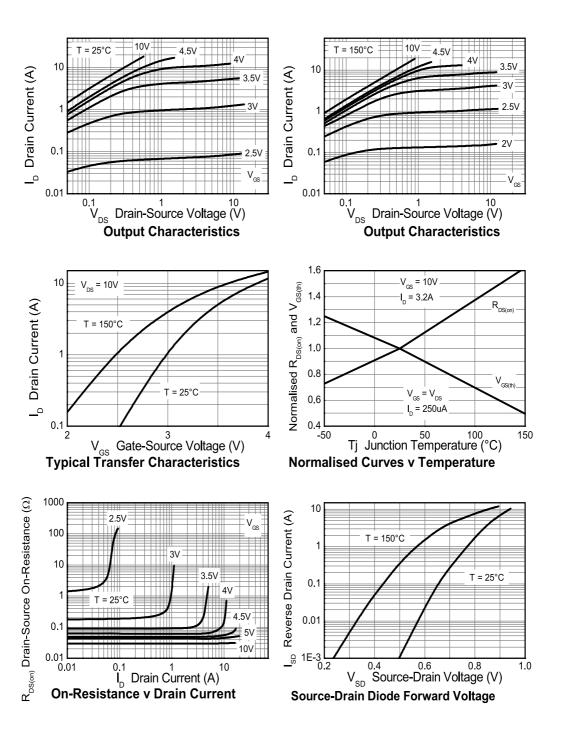
NOTES:

^(*) Measured under pulsed conditions. Pulse width \leq 300 μ s; duty cycle \leq 2%.

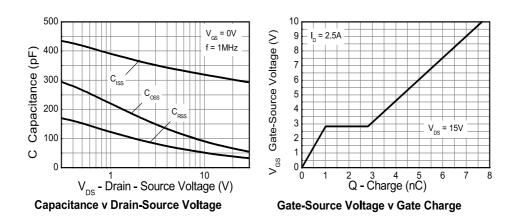
^(†) For design aid only, not subject to production testing.

^(‡) Switching characteristics are independent of operating junction temperature.

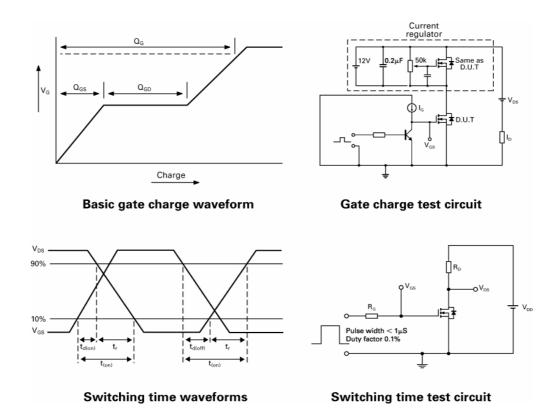
Typical characteristics



Typical characteristics

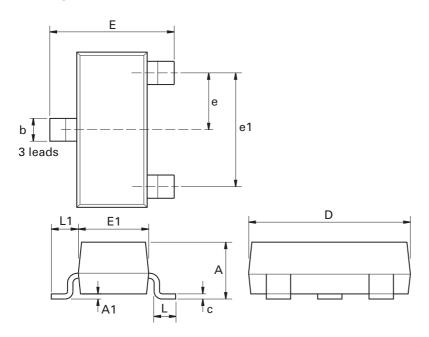


Test circuits



ZXMN3F30FH

Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	-	1.12	-	0.044	e1	1.90	NOM	0.075	NOM
A1	0.01	0.10	0.0004	0.004	Е	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.20	0.003	0.008	L	0.25	0.60	0.0098	0.0236
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.037	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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